

Embedded instrumentation toolbox for screening marginal defects and outliers for production

Odintsov, Sergei; Jutman, Artur; Devadze, Sergei; Alekseyev, Igor IEEE AUTOTESTCON 2017 : Schaumburg, USA, Sept 11-14, 2017 : proceedings 2017 / p. 336-334 : ill <https://doi.org/10.1109/AUTEST.2017.8080516>

FPGA-based synthetic instrumentation for board test

Alekseyev, Igor; Jutman, Artur; Devadze, Sergei; Odintsov, Sergei; Wenzel, Thomas Proceedings : International Test Conference 2012 2012 / p. 1-10 : ill <https://ieeexplore.ieee.org/document/6401571>

In-field detection of degradation on PCB assembly high-speed buses

Odintsov, Sergei IEEE AUTOTESTCON 2018 : National Harbor, September 17-20, 2018 : proceedings 2018 / 6 p.: ill <https://doi.org/10.1109/AUTEST.2018.8532547>

Marginal PCB assembly defect detection on DDR3/4 memory bus

Odintsov, Sergei; Jutman, Artur; Devadze, Sergei 2017 IEEE International Test Conference (ITC 2017) : Forth Worth, Texas, USA, 31 October - 2 November 2017 2017 / p. 238-247 : ill <https://doi.org/10.1109/TEST.2017.8242070> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

A new FPGA-based detection method for spurious variations in PCBA power distribution network

Odintsov, Sergei; Bozzoli, Ludovica; De Sio, Corrado; Sterpone, Luca; Jutman, Artur 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/DDECS.2019.8724662>

Ways for board and system test to benefit from FPGA embedded instrumentation

Ehrenberg, Heiko; Odintsov, Sergei; Devadze, Sergei; Jutman, Artur; Alekseyev, Igor; Wenzel, Thomas 2019 IEEE AUTOTESTCON 2019 / 10 p : ill <https://doi.org/10.1109/AUTOTESTCON43700.2019.8961057>